

<b>Notice of References Cited</b>	Application/Control No. 10/054,561		Applicant(s)/Patent Under Reexamination CHAN ET AL.	
	Examiner DuyVu n Deo		Art Unit 1765	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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✕	B	US-6,432,772	08-2002	Wu et al.	438255
✕	C	US-6,399,440	06-2002	Miao	438/255
✕	D	US-6,376,326	04-2002	Lou	438/396
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**NON-PATENT DOCUMENTS**

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